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**NOTICE OF FILING/CLAIM FEE(S) DUE**  
TO ENSURE PROPER CREDIT OF FEES, PLEASE RETURN A COPY OF THIS  
FEE CALCULATION SHEET WITH YOUR RESPONSE.

APPLICATION NUMBER: 08 918288

**Total Fee Calculation**

|                                     | Fee Code       | Total<br># Claims | Number<br>Extra | X         | Fee        | Fee =        | Total         |
|-------------------------------------|----------------|-------------------|-----------------|-----------|------------|--------------|---------------|
|                                     | Sm./Lg.        |                   |                 |           | Sm. Entity | Lg. Entity   |               |
| Basic Filing Fee                    | <u>201/101</u> |                   |                 |           |            | <u>770.-</u> | <u>770.-</u>  |
| Total Claims >20                    | <u>203/103</u> | <u>40</u>         | -20 =           | <u>20</u> | X          | <u>22.-</u>  | <u>440.-</u>  |
| Independent Claims >3               | <u>202/102</u> | <u>1</u>          | -3 =            |           | X          |              |               |
| Mult. Dep Claim Present             | <u>204/104</u> |                   |                 |           |            |              |               |
| Surcharge                           | <u>205/105</u> |                   |                 |           |            | <u>130.-</u> | <u>130.-</u>  |
| English Translation                 | <u>139</u>     |                   |                 |           |            |              |               |
| <b><u>TOTAL FEE CALCULATION</u></b> |                |                   |                 |           |            |              | <u>1340.-</u> |

Fees due upon filing the application:

Total Filing Fees Due = \$ 1340.-

Less Filing Fees Submitted - \$ —

**BALANCE DUE** = \$ 1340.-

Office of Initial Patent Examination